4N40K-MT Power MOSFET

4A, 400V N-CHANNEL POWER MOSFET

■ DESCRIPTION

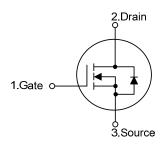
The UTC **4N40K-MT** is a N-channel mode power MOSFET using UTC's advanced technology to provide customers with planar stripe and DMOS technology. This technology specializes in allowing a minimum on-state resistance and superior switching performance. It also can withstand high energy pulse in the avalanche and commutation mode.

The UTC **4N40K-MT** is universally applied in electronic lamp ballast based on half bridge topology and high efficient switched mode power supply.



- * $R_{DS(ON)}$ < 1.4 Ω @ V_{GS} = 10 V, I_D = 2.0 A
- * High switching speed
- * 100% avalanche tested

■ SYMBOL

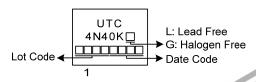


ORDERING INFORMATION

Ordering Number		Doolsogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
4N40KL-TN3-R	4N40KG-TN3-R	TO-252	G	D	S	Tape Reel	
Note: Pin Assignment: G: G	e				_		

4N40KG-TN3-R
(1)Packing Type
(1) R: Tape Reel
(2) TN3: TO-252
(3) G: Halogen Free and Lead Free, L: Lead Free

■ MARKING



1 TO-252

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ABSOLUTE MAXIMUM RATINGS (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V _{DSS}	400	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous (T _C =25°C)	I _D	4	Α	
Drain Gurient	Pulsed (Note 2)	I _{DM}	8	Α	
Avalanche Energy Single Pulsed (Note 3)		E _{AS}	116	mJ	
Peak Diode Recovery dy	v/dt (Note 4)	dv/dt	4.5	V/ns	
Power Dissipation		P_D	50	W	
Junction Temperature		T_J	+150	°C	
Storage Temperature		T _{STG}	-55 ~ + 150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=18mH, I_{AS} =3.6A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} = 25°C
- 4. $I_{SD} \le 4.0A$, di/dt $\le 100A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C

THERMAL DATA

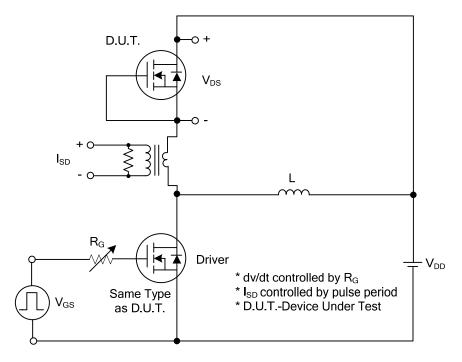
PARAMETER	SYMBOL	SYMBOL RATINGS	
Junction to Ambient	θ_{JA}	110	°C/W
Junction to Case	θјс	2.5	°C/W

ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

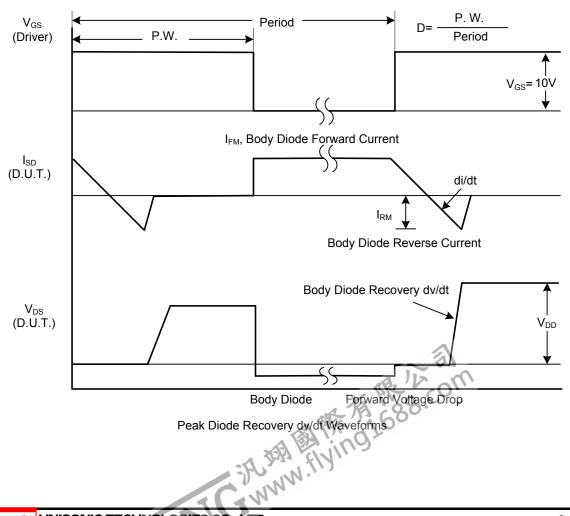
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT			
OFF CHARACTERISTICS									
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	400			V			
Drain-Source Leakage Current	I _{DSS}	V _{DS} =400V, V _{GS} =0V			10	μA			
Forward	I _{GSS}	V _{GS} =+30V, V _{DS} =0V			+100	nA			
Gate- Source Leakage Current Reverse		V _{GS} =-30V, V _{DS} =0V			-100	nΑ			
ON CHARACTERISTICS									
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$			4.0	V			
Static Drain-Source On-State Resistance	R _{DS(ON)}	V_{GS} =10V, I_D =2.0A		1.2	1.4	Ω			
DYNAMIC PARAMETERS									
Input Capacitance	C_{ISS}			400		pF			
Output Capacitance	Coss	V_{GS} =0V, V_{DS} =25V, f=1.0MHz		56		pF			
Reverse Transfer Capacitance	C_{RSS}			4.5		pF			
SWITCHING PARAMETERS									
Total Gate Charge	Q_G	1/ 100// 1/ 10// 1 10/		11.5		nC			
Gate to Source Charge	Q_GS	V _{DS} =100V, V _{GS} =10V, I _D =4.0A, I _G =1mA (Note 1, 2)		4.6		nC			
Gate to Drain Charge	Q_GD	IG-IIIIA (NOte 1, 2)		2		nC			
Turn-ON Delay Time	$t_{D(ON)}$			6		ns			
Rise Time	t_R	V_{DS} =100V, V_{GS} =10V, I_{D} =4.0A,		15		ns			
Turn-OFF Delay Time	t _{D(OFF)}	R _G =25Ω (Note1,2)		23		ns			
Fall-Time	t_{F}			22		ns			
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS									
Maximum Body-Diode Continuous Current	I_{SD}	~ ***			4	Α			
Maximum Body-Diode Pulsed Current	I _{SM}	WE COM			8	Α			
Drain-Source Diode Forward Voltage	V_{SD}	I _S =4.0A, V _{GS} =0V			1.5	٧			
Reverse Recovery Time (Note 1)	t _{rr}	1 = 4 00 V - 00 QL (dt=4000 /::=		190		nS			
Reverse Recovery Charge	Qrr	I_S =4.0A, V_{GS} =0V, dI_F/dt =100A/ μ s		1.28		μC			

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%. 2. Essentially independent of operating temperature.

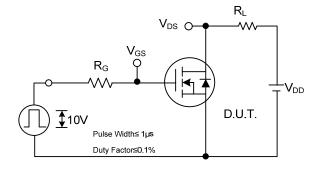
TEST CIRCUITS AND WAVEFORMS



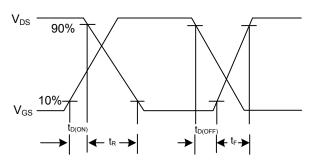
Peak Diode Recovery dv/dt Test Circuit



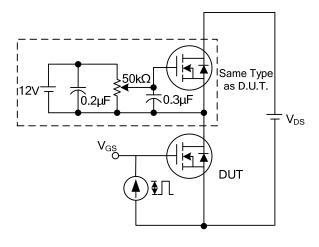
TEST CIRCUITS AND WAVEFORMS (Cont.)



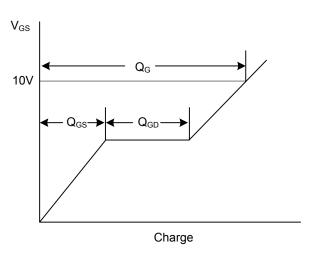
Switching Test Circuit



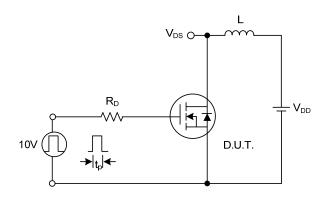
Switching Waveforms



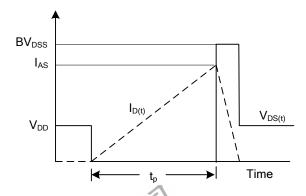
Gate Charge Test Circuit



Gate Charge Waveform



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms

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